

14. (Amended) A suspension assembly comprising:
a slider/head assembly;
a suspension having electrically conducting paths; and
an interconnect module coupled between said suspension and said slider/head assembly to route one or more data signals between said [suspension] electrically conducting paths and said slider/head assembly.

17. (Amended) The suspension assembly of claim 16, wherein said slider/head assembly is [orthogonally] orthogonally mounted onto said suspension.

18. (Amended) A suspension assembly comprising:
a slider/head assembly;
a suspension having electrically conducting paths;
a microactuator; and
an interconnect module coupled between said suspension and said microactuator to route one or more data signals between said [suspension] electrically conducting paths and said microactuator.

21. An assembly, comprising:
a first device;
a second device having electrically conducting paths; and
an interconnect device coupled between said first and second devices to route one or more signals between said first device and [second devices] said electrically conducting paths.

24. (Amended) A storage device, comprising:
a disk;
a spindle motor positioned to support and rotate said disk;
a suspension assembly including an interconnect module coupled between a slider/head assembly and a suspension, said suspension having electrically conducting paths, and said interconnect module routing [to route] one or more data signals between said [suspension] electrically conducting paths and said slider/head assembly; and

an actuator coupled to said suspension assembly and operable to position said suspension assembly above said disk to access said disk for reading and/or writing operations.

27. (Amended) A test system for disks, comprising:
a spindle motor for rotating a disk during a test operation; and
a test platform including a suspension assembly coupled to an actuator, said actuator operable to position said suspension assembly above said disk to access said disk for said test operation, said suspension assembly including an interconnect module coupled between a slider/head assembly and a suspension, said suspension having electrically conducting paths, and said interconnect module routing [to route] one or more data signals between said [suspension] electrically conducting paths and said slider/head assembly.

30. (Amended) The test system of claim 29, wherein said slider/head assembly is [orthogonally] orthogonally mounted on said suspension.

31. (Amended) A storage device, comprising:
a disk;
a spindle motor positioned to support and rotate said disk;
a suspension assembly including an interconnect module coupled between a suspension having electrically conducting paths and a microactuator to route data signals between said [suspension] said electrically conducting paths and said microactuator; and
an actuator coupled to said suspension assembly and operable to position said suspension assembly above said disk to access said disk for reading and/or writing operations.

34. (Amended) A test system for disks, comprising:
a spindle motor for rotating a disk during a test operation; and
a test platform including a suspension assembly coupled to an actuator, said actuator operable to position said suspension assembly above said disk to access said disk for said test operation, said suspension assembly including an interconnect module coupled between a

af suspension ~~having electrically conducting paths~~ and a microactuator to route data signals between said [suspension] ~~electrically conducting paths~~ and said microactuator.

af 37. (Amended) The test system of claim 36, wherein said slider/head assembly is [orthogonally] ~~orthogonally~~ mounted onto said suspension.

Please add the following new claims:

-- 38. (New) The suspension assembly of claim 14, wherein said electrically conducting paths are attached to said suspension.

39. (New) The suspension assembly of claim 18, wherein said electrically conducting paths are attached to said suspension.

af 40. (New) The assembly of claim 21, wherein said electrically conducting paths are attached to said second device.

41. (New) The test system of claim 27, wherein said electrically conducting paths are attached to said suspension.

42. (New) The storage device of claim 31, wherein said electrically conducting paths are attached to said suspension.

43. (New) The test system of claim 34, wherein said electrically conducting paths are attached to said suspension. --

REMARKS

The Examiner has made a restriction requirement and has required the Applicants to select the invention as claimed in claims 1-13 or the invention as claimed in claims 14-37 for prosecution in this application. Applicants hereby elect to prosecute the invention as claimed in claims 14-37 in this application without traverse.